

An indirect method to measure the electric charge deposited on insulators during PIXE analysis

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Total charge deposited by a proton beam in an insulator during PIXE analysis has been indirectly determined using a Mylar film coated with cobalt. Elemental concentrations in the samples, pieces of volcanic glass, were obtained and compared to concentrations determined by ICP OES on the same samples. The strong agreement between these results shows the accuracy of the charge determined by this method. © 2007 Elsevier B.V. All rights reserved.